## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10561014	PAN ET AL.
Examiner	Art Unit
Chang-Yu Wang	1649

SEARCHED		
Class Subclass Date Examiner		Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Sequence search: SEQ ID NOs:1, 3 and 36 regular and oligomer search. See search results in SCORE (6/18/08).	9/28/11	CYW
EAST, STN: search strategy attached (updated).	9/28/11	CYW
Inventor name search: EAST, STN, PALM (updated).	9/28/11	CYW
PLUS search from STIC. See search results in eDAN (9/28/11).	9/28/11	CYW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/C.Y. W./ Examiner.Art Unit 1649	

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